

AMENDMENTS TO THE CLAIMS

1. (currently amended) A package assembly for an electronic device, comprising:
 - a substrate having a first surface with a first plurality of contact pads and a second plurality of contact pads, a second surface with a plurality of connection pads, and a plurality of via holes connecting said first plurality of contact pads and said plurality of connection pads; and
 - a buffer layer between said substrate and said electronic device, and a surface of said electronic device having electrodes being opposite to said first surface of said substrate, said buffer layer having an opening to expose said first plurality of contact pads, wherein said buffer layer has a first part with a first density and a second part with a second density, said first density greater than said second density, wherein said second part of said buffer layer surrounds the edge of said electronic device and said first part of said buffer layer is configured with said electronic device such that said buffer layer functions as a self-planarization buffer between said electronic device and said substrate for increasing the hermeticity thereof~~a fastening face of said edge of said electronic device and said buffer layer is unflattened.~~
2. (currently amended) The package assembly in claim 1, wherein said substrate is selected from the group consisting of an aluminum~~A1~~ substrate, a ceramic substrate, a silicon substrate, a polymer substrate, and a glass substrate.
3. (original) The package assembly in claim 1, wherein said buffer layer is selected from the group consisting of an organic film layer and a polymer film layer.
4. (original) The package assembly in claim 1, wherein said buffer layer is conductive.

5. (cancelled)

6. (cancelled)

7. (original) The package assembly in claim 1, further comprises a conductive layer formed on said electronic device.

8. (original) The package assembly in claim 1, wherein said buffer layer has a thickness of 30-200 microns.

9. (original) The package assembly in claim 1, wherein said fastening face of said edge of said electronic device and said buffer layer has a corner.

10. (cancelled)

11. (original) The package assembly in claim 1, wherein said electronic device is a surface acoustic wave device.

12. (currently amended) A package assembly for a plurality of electronic devices, comprising:

a substrate having a first surface with a first plurality of contact pads and a second plurality of contact pads, a second surface with a plurality of connection pads, and a plurality of via holes connecting said first plurality of contact pads and said plurality of connection pads; and

a buffer layer having a plurality of openings to expose said first plurality of contact pads, and said plurality of electronic devices being on said plurality of openings respectively, wherein a respective surface of said plurality of electronic devices having electrodes is opposite to said first surface of said substrate, wherein said buffer layer has a first part with a first density and a

second part with a second density, said first density greater than said second density, wherein said second part of said buffer layer surrounds the edge of said plurality of electronic devices and said first part of said buffer layer is configured with said plurality of electronic devices such that said buffer layer functions as a self-planarization buffer between said electronic device and said substrate for increasing the hermeticity thereof, and fastening faces of said edge of said plurality of electronic devices and said buffer layer are unflattened.

13. (currently amended) The package assembly in claim 12, wherein said substrate is selected from the group consisting of an aluminum-A1 substrate, a ceramic substrate, a silicon substrate, a polymer substrate, and a glass substrate.

14. (original) The package assembly in claim 12, wherein said buffer layer is selected from the group consisting of an organic film layer and a polymer film layer.

15. (original) The package assembly in claim 12, wherein said buffer layer is conductive.

16. (cancelled)

17. (original) The package assembly in claim 12, further comprises a conductive layer formed on said plurality of electronic devices.

18. (original) The package assembly in claim 12, wherein said buffer layer has a thickness of 30-200 microns.

19. (original) The package assembly in claim 12, wherein said fastening faces of said edge of said plurality of electronic devices and said buffer layer have a corner respectively.

20. (cancelled)

21. (original) The package assembly in claim 12, wherein said plurality of electronic devices is a surface acoustic wave device.

22. – 33. (cancelled)